## Deposition of Organic Monolayer Film on TMDC-FET for Doping and Atomic Layer Deposition

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The doping effect is one of the most critical considerations in the practical utilization of 2-dimensional (2D) materials, such as transition metal dichalcogenides (TMDCs), as channel materials for 2D field-effect transistors (FETs) in future logic circuits. In this study, we demonstrate p-type doping for a fewlayer crystal of WSe<sub>2</sub> through charge transfer doping using an organic monolayer formed on the WSe<sub>2</sub>. Hexafluoro-tetracyano-naphthoquinodimethane (F6-TCNNO) is one of the promising molecules for acceptor doping due to its electron affinity level, which is deeper than the valence band edge of monolayer WSe<sub>2</sub>. Additionally, it possesses a flat molecular structure and highly electron-attracting characteristics due to the presence of halogen atoms. Such an organic monolayer could prove useful as a seed layer for the atomic layer deposition (ALD) of high-kmetal oxides in 2D-FETs composed of TMDCs for future VLSI applications [1]. Using a vacuum-tube furnace, we have achieved selective growth of the F6-TCNNO monolayer on a WSe<sub>2</sub>-FET at an appropriate temperature without deposition occurring on other regions such as metal electrodes and SiO<sub>2</sub> on

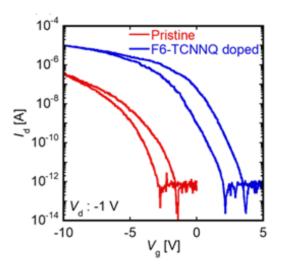


Fig.1. Transfer curves before and after F6-TCNNQ deposition.

the substrate. Following the deposition process, a clear positive shift in the threshold voltage was observed without any degradation in mobility or the on/off ratio, as depicted in Fig. 1. Furthermore, we have confirmed that the contact resistance between the metal (Pd or Pt) and the WSe<sub>2</sub> has been significantly improved by more than one order of magnitude after the deposition of F6-TCNNQ on top of the FET channel, showcasing its secondary effects. Utilizing the organic monolayer as a seed layer, our ongoing efforts involve depositing high-*k* metal oxide on the WSe<sub>2</sub> by ALD. This research is supported by Tokyo Electron Limited.

## References

[1] W. Li et al., Nature Electronics, 2, 563 (2019).